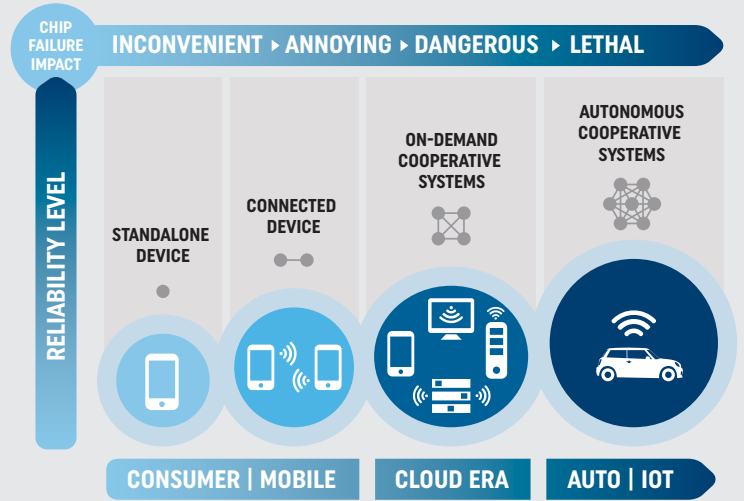


RELIABILITY CALIBRATES THE SEMICONDUCTORS TECHNOLOGY

ELES provides the Customers with reliability testing solutions for Logic, MEMS, Memory and Smart Power ICs, Sic & GaN and Photonics.

We are focused on providing effective support to achieve Zero Defects with a 100% Yield, for the possible best competitiveness and sustainability, establishing a mutually beneficial partnership with our Customers, worldwide. Our **Unique Proposition** originates from the SERVICIZATION business model (sell solutions and deliver results). We offer turnkey solutions on Reliability Test consisting of peculiar Test Systems combining Stress and Test on the same platform, Applications (Test Program and Fixtures), Test Development and Simulation SW suite, Data Analysis Tools and Results Support Services.



Powered by ELES RETE to achieve **Design Robustness, Process Optimization, Fast Maturity** during qualification

ZERO ESCAPE DURING QUALIFICATION 100% YIELD IN MANUFACTURING



For devices from 0 to more than 1.000W

Powered by ELES RETE for **Augmented (or maximization) Stress and Test coverage with dedicated HW and SW Algorithms IPs to reach**

- Zero Escape qualification
- Liquid-cooling and Air-cooling mode for reliability test cost optimization
- No risk to damage electronics in case of leakages
- Controlled temperature in the oven to avoid the stress of electronic components on board
- Purge with nitrogen or dry air to avoid DUTs oxidation
- Single device temperature control
- Automatic calculation of DUTs Equivalent Lifetime
- Large device observability and extended data collection
- Dedicated SW tools to support data interpretation and statistical analysis



SMART MTX

All-in-one Reliability Test System for Smart Power device, SiC & GaN



- Enhanced Fault Triggering and Detection intercept all device weakness according to RETE TfR approach.
- Satisfy the most stringent qualification like Automotive “Grade-0”, temperature range -40°C to 175°C
- Power Temperature Cycling capability according to JESD22-A105C
- High Voltage (up to 6KV) & High Current
- Possibility to connect external loads for test in application mode for a more effective stress
- System Health & Environment Monitor to maximize Overall Equipment Efficiency
- Modular & Scalable platform

SMART MTX

High-parallelism test during burn-in platform for high-power SOC devices, from 5W to 1 KW (es. ADAS, Networking, Cloud Computing, AI)

- Best-in-Class Solution in Cost of Ownership.
- Enhanced Fault Triggering and Detection towards Zero Defect production inline with RETE TfR approach.
- Enabling safe HV Stress.
- Ready to be integrated in a fully automated manufacturing flow according to Industry 4.0
- Standard 3D Test Fixture, compatible with automated production flow and reusable for different test applications
- System Health & Environment Monitor to maximize Overall Equipment Efficiency
- Modular & Scalable platform



ELES is world class leader in the Semiconductor Test Industry, providing systems, solutions and methodologies to ensure a high reliability production and to achieve Zero Defects and Zero Scraps.

